

# **PRODUCT CHANGE NOTICE**

**Data Sheet Specification  
Change for Intersil Product  
ISL25700FRUZ\***

**Refer to:  
PCN14046**

**Date: July 23, 2014**

July 23, 2014

To: Our Valued Intersil Customers

Subject: **Data Sheet Specification Change for Intersil Product ISL25700FRUZ\***

This notice is to inform you that Intersil has changed the data sheet specification for the ISL25700FRUZ\* products. The change to the Electrical Specification for leakage current on the SDA and SCL pins ( $I_{LkDig}$ ) from  $\pm 2\mu A$  to  $\pm 3\mu A$ . The change aligns the data sheet with the product characteristics and is necessary to maintain product manufacturability in support of customer delivery requirements. Details regarding the change are contained on the following page. The updated data sheet is available on the Intersil web site at:

<http://www.intersil.com/content/dam/Intersil/documents/fn68/fn6885.pdf>.

Products affected: ISL25700FRUZ-T ISL25700FRUZ-TK ISL25700FRUZ-T7A

There have been no changes to the die/silicon or product itself. There will be no change in the external marking of the packaged parts.

Intersil will take all necessary actions to conform to agreed upon customer requirements and to ensure the continued high quality and reliability of Intersil products being supplied. Customers may expect to receive product electrically screened to the revised data sheet beginning *ninety* days from the date of this notification or earlier with approval.

If you have concerns with this advisory, Intersil must hear from you promptly. Please contact the nearest Intersil Sales Office or call the Intersil Corporate line at 1-888-468-3774, in the United States, or 1-321-724-7143 outside of the United States.

Regards,



Jeffrey Touvell

Intersil Corporation

PCN14046

CC: M. Carmody D. Goodhew P. Lee

# PCN14046 Data Sheet Change

## From:

SYMBOL	PARAMETER	TEST CONDITIONS	MIN (Note 13)	TYP (Note 6)	MAX (Note 13)	UNITS
I <sub>DD1</sub>	V <sub>DD</sub> Supply Current (Non-Volatile Write/read)	f <sub>SCL</sub> = 400kHz; SDA = Open; (for I <sup>2</sup> C, Active, Read and Write States) I <sub>PMOS</sub> = 0mA, DAC unload			4	mA
I <sub>DD2</sub>	V <sub>DD</sub> Supply Current (Volatile Write/read)	I <sub>PMOS</sub> = 0mA, DAC unload			2.8	mA
I <sub>LkgDig</sub>	Leakage Current, at SDA and SCL Pins	Voltage at pin from GND to VCC	-2		2	μA

## To:

SYMBOL	PARAMETER	TEST CONDITIONS	MIN (Note 13)	TYP (Note 6)	MAX (Note 13)	UNITS
I <sub>DD1</sub>	V <sub>DD</sub> Supply Current (Non-Volatile Write/read)	f <sub>SCL</sub> = 400kHz; SDA = Open; (for I <sup>2</sup> C, Active, Read and Write States) I <sub>PMOS</sub> = 0mA, DAC unload			4	mA
I <sub>DD2</sub>	V <sub>DD</sub> Supply Current (Volatile Write/read)	I <sub>PMOS</sub> = 0mA, DAC unload			2.8	mA
I <sub>LkgDig</sub>	Leakage Current, at SDA and SCL Pins	Voltage at pin from GND to VCC	-3		3	μA

**Note: Changes are shaded in yellow**